Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination
10/630,683	CHEN, YI-CHEN
Examiner	Art Unit
Navneet Sonia Khaira	3754

	SEAR	CHED	
Class	Subclass	Date	Examiner
222	129,181.1, 153.01	4/4/2005	NK
222	153.03	4/4/2005	NK
222	160,173	4/4/2005	NK
222	493	4/4/2005	NK
	-		

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
	<u></u>		
-			

SEARCH N (INCLUDING SEARC	SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR	
		:	
		ļ	
_			
	7.11.2		